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U.S. PATENT AND TRADEMARK OFFICE

Attorney Docket No. 35640/36899

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Applicant(s): Matsumoto Toshiyuki et al. Conf. No.: 2544
Serial No.: 09/703,845 Art Unit: 2829
Filed: November 2, 2000 Examiner: Nguyen, Tung X.
For: CAPACITANCE MEASUREMENT METHOD OF MICRO
STRUCTURES OF INTEGRATED CIRCUITS

AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the official Office Action dated May 25, 2004, please amend the above-identified application as follows:

IN THE CLAIMS

Please see the Claim Summary Document attached hereto.

REMARKS

In response to the official Office Action dated May 25, 2004, Applicant provides the following remarks.

With respect to the objection of the drawings under 37 C.F.R. § 1.83(a) and the rejection of Claim 2 under 35 U.S.C. § 112, the third terminals are the guard terminals T_G shown in various figures. In Figure 12, the two guard terminals T_G are Cbb2 and Cbj. In Figure 13, the two guard terminals T_G are Cbp and Cbj. In Figure 19, the guard terminals T_G are Cwp and Cwg. In Figure 22, the guard terminals T_G are elements 104 and 106. Thus, there is sufficient support in the drawings for a plurality of third terminals.

The allowance of Claims 20-22 is hereby acknowledged. The objection to Claims 3-5, 8 and 11-19 as being directed to allowable subject matter is also acknowledged.

Objected to Claim 4 has been rewritten as an independent claim. Basically, the preamble of Claim 1 has been inserted, and the redundant parts from Claim 1 have not been included. Thus, Claim 4 is considered allowable.